- Noninverting Buffers With Open-Collector Outputs
- Package Options Include Plastic Small-Outline (D) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

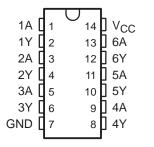
These devices contain six independent noninverting buffers. They perform the Boolean function Y = A. The open-collector outputs require pullup resistors to perform correctly. They may be connected to other open-collector outputs to implement active-low wired-OR or active-high wired-AND functions. Open-collector devices are often used to generate higher V_{OH} levels.

The SN54ALS1035 is characterized for operation over the full military temperature range of -55° C to 125°C. The SN74ALS1035 is characterized for operation from 0°C to 70°C.

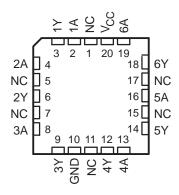
FUNCTION TABLE (each buffer)

INPUT A	OUTPUT Y					
Н	Н					
L	L					

SN54ALS1035...J PACKAGE SN74ALS1035...D OR N PACKAGE (TOP VIEW)

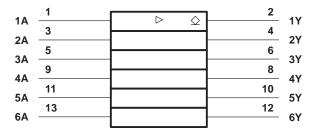


SN54ALS1035...FK PACKAGE (TOP VIEW)



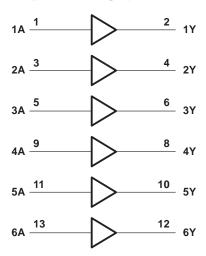
NC - No internal connection

logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



Pin numbers shown are for the D, J, and N packages.

SN54ALS1035, SN74ALS1035 HEX NONINVERTING BUFFERS WITH OPEN-COLLECTOR OUTPUTS

SDAS243A - APRIL 1982 - REVISED JANUARY 1995

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}		7 V
Input voltage, V _I		7 V
Off-state output voltage		7 V
Operating free-air temperature range, TA: SN54ALS103	5	-55°C to 125°C
SN74ALS103	5	0°C to 70°C
Storage temperature range		-65°C to 150°C

recommended operating conditions

		SN54ALS1035			SN74ALS1035			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V _{IH}	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.7			0.8	V
Vон	High-level output voltage	5.5		5.5	V			
IOL	Low-level output current	12				24	mA	
TA	Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		SN54ALS1035			SN74ALS1035			UNIT
			MIN T	гүр‡	MAX	MIN	TYP [‡]	MAX	UNII
VIK	$V_{CC} = 4.5 \text{ V},$	$I_{I} = -18 \text{ mA}$			-1.5			-1.5	V
Voi	V _{CC} = 4.5 V	I _{OL} = 12 mA		0.25	0.4		0.25	0.4	V
V _{OL}		I _{OL} = 24 mA					0.35	0.5	V
ЮН	$V_{CC} = 4.5 \text{ V},$	V _{OH} = 5.5 V			0.1			0.1	V
lį	$V_{CC} = 5.5 \text{ V},$	V _I = 7 V			0.1			0.1	mA
lіН	$V_{CC} = 5.5 \text{ V},$	V _I = 2.7 V			20			20	μΑ
I _{IL}	$V_{CC} = 5.5 \text{ V},$	V _I = 0.4 V			-0.1			-0.1	mA
Іссн	$V_{CC} = 5.5 \text{ V},$	V _I = 4.5 V		3	6		3	6	mA
l _{CCL}	$V_{CC} = 5.5 \text{ V},$	V _I = 0		8	14		8	14	mA

 $[\]ddagger$ All typical values are at V_{CC} = 5 V, T_A = 25°C.

switching characteristics (see Figure 1)

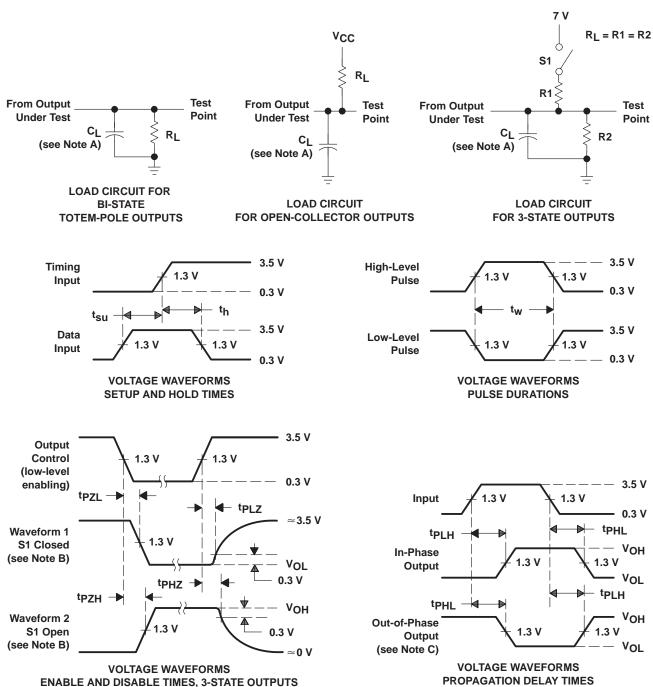
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _C (C _L R _L T _A	UNIT			
			MIN	MAX	MIN	MAX	
t _{PLH}	t _{PLH} A	Y	5	35	5	30	
t _{PHL}			2	14	2	12	ns

[§] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

PARAMETER MEASUREMENT INFORMATION SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: PRR \leq 1 MHz, $t_r = t_f = 2$ ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



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